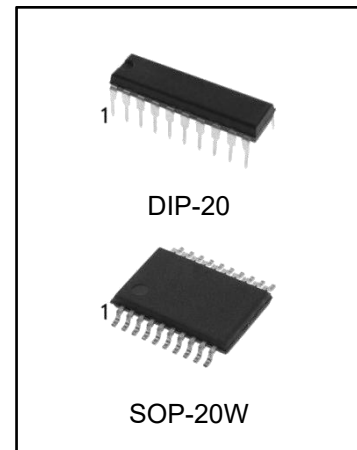


12-BIT ANALOG-TO-DIGITAL CONVERTERS WITH SERIAL CONTROL AND 11 ANALOG INPUTS

Features

- 12-Bit-Resolution A/D Converter
- 10- μ s Conversion Time Over Operating Temperature
- 11 Analog Input Channels
- 3 Built-In Self-Test Modes
- Inherent Sample-and-Hold Function
- Linearity Error ... \pm 1 LSB Max
- On-Chip System Clock
- End-of-Conversion Output
- Unipolar or Bipolar Output Operation (Signed Binary With Respect to 1/2 the Applied Voltage Reference)
- Programmable MSB or LSB First
- Programmable Power Down
- Programmable Output Data Length
- CMOS Technology
- Application Report Available



Ordering Information

| DEVICE | Package Type | MARKING | Packing | Packing Qty |
|-------------|--------------|----------|---------|--------------|
| TLC2543CPG | DIP-20 | TLC2543C | TUBE | 18pcs/tube |
| TLC2543IPG | DIP-20 | TLC2543I | TUBE | 18pcs/tube |
| TLC2543CDRG | SOP-20W | TLC2543C | REEL | 2000pcs/reel |
| TLC2543IDRG | SOP-20W | TLC2543I | REEL | 2000pcs/reel |

Description

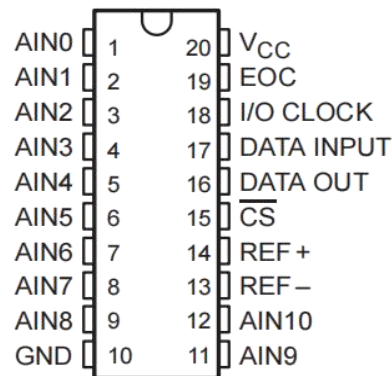
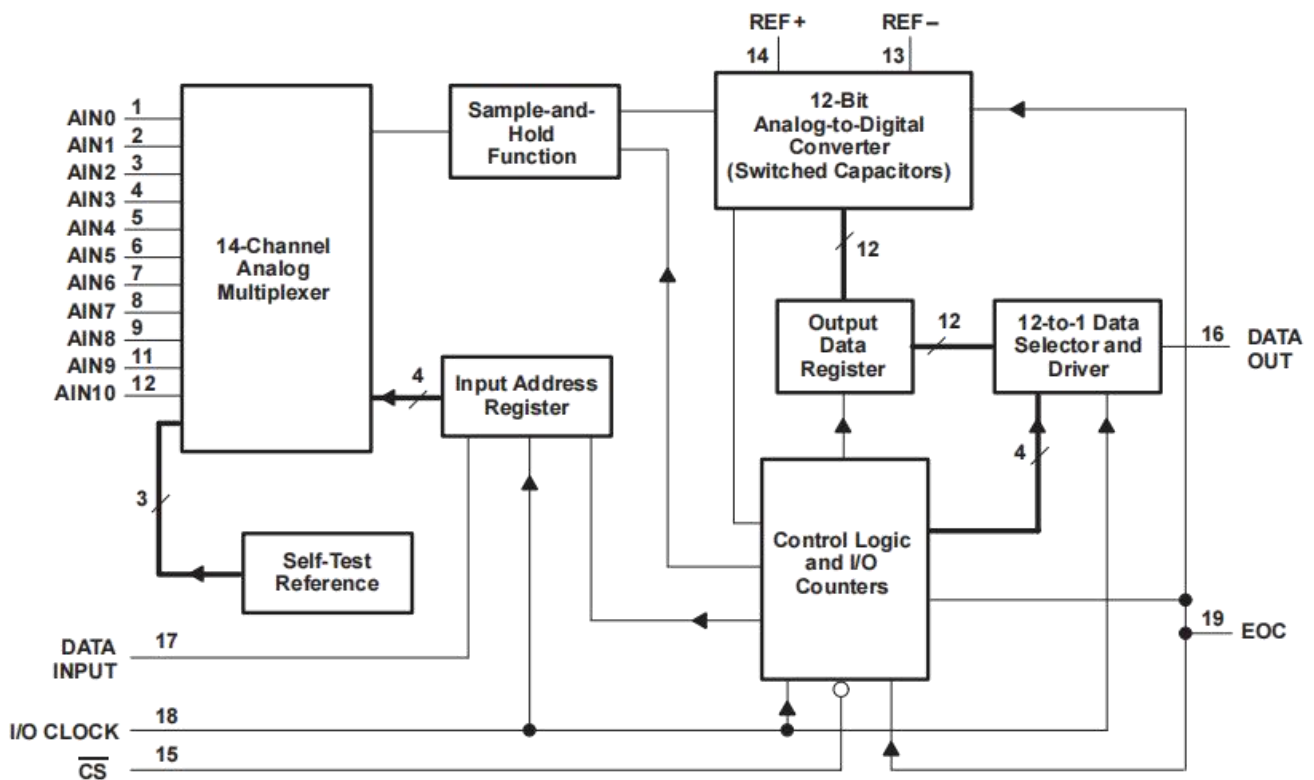
The TLC2543C and TLC2543I are 12-bit, switched- capacitor, successive-approximation, analog-to- digital converters. Each device has three control inputs [chip select (CS), the input-output clock (I/O CLOCK), and the address input (DATA INPUT)] and is designed for communication with the serial port of a host processor or peripheral through a serial 3-state output. The device allows high-speed data transfers from the host.

In addition to the high-speed converter and versatile control capability, the device has an on-chip 14-channel multiplexer that can select any one of 11 inputs or any one of three internal self-test voltages. The sample-and-hold function is automatic. At the end of conversion, the end-of-conversion (EOC) output goes high to indicate that conversion is complete. The converter incorporated in the device features differential high-impedance reference inputs that facilitate ratiometric conversion, scaling, and isolation of analog circuitry from logic and supply noise. A switched-capacitor design allows low-error conversion over the full operating temperature range.

The TLC2543C is characterized for operation from $T_A = 0^{\circ}\text{C}$ to 70°C . The TLC2543I is characterized for operation from $T_A = -40^{\circ}\text{C}$ to 85°C .

Pin Configuration

DIP-20/SOP-20W


functional block diagram


Terminal Functions

| TERMINAL NAME NO. | I/O | DESCRIPTION |
|--------------------------------|-----|---|
| AIN0 – AIN10 1–9, 11, 12 | I | Analog input. These 11 analog-signal inputs are internally multiplexed. The driving source impedance should be less than or equal to 50Ω for 4.1-MHz I/O CLOCK operation and be capable of slewing the analog input voltage into a capacitance of 60 pF. |
| \overline{CS} 15 | I | Chip select. A high-to-low transition on \overline{CS} resets the internal counters and controls and enables DATA OUT, DATA INPUT, and I/O CLOCK. A low-to-high transition disables DATA INPUT and I/O CLOCK within a setup time. |
| DATA INPUT 17 | I | Serial-data input. A 4-bit serial address selects the desired analog input or test voltage to be converted next. The serial data is presented with the MSB first and is shifted in on the first four rising edges of I/O CLOCK. After the four address bits are read into the address register, I/O CLOCK clocks the remaining bits in order. |
| DATA OUT 16 | O | The 3-state serial output for the A/D conversion result. DATA OUT is in the high-impedance state when \overline{CS} is high and active when \overline{CS} is low. With a valid CS, DATA OUT is removed from the high-impedance state and is driven to the logic level corresponding to the MSB/LSB† value of the previous conversion result. The next falling edge of I/O CLOCK drives DATA OUT to the logic level corresponding to the next MSB / LSB, and the remaining bits are shifted out in order. |
| EOC 19 | O | End of conversion. EOC goes from a high to a low logic level after the falling edge of the last I/O CLOCK and remains low until the conversion is complete and the data is ready for transfer. |
| GND 10 | | Ground. GND is the ground return terminal for the internal circuitry. Unless otherwise noted, all voltage measurements are with respect to GND. |
| I/O CLOCK 18 | I | Input/output clock. I/O CLOCK receives the serial input and performs the following four functions: It clocks the eight input data bits into the input data register on the first eight rising edges of I/O CLOCK with the multiplexer address available after the fourth rising edge. On the fourth falling edge of I/O CLOCK, the analog input voltage on the selected multiplexer input begins charging the capacitor array and continues to do so until the last falling edge of the I/O CLOCK. It shifts the 11 remaining bits of the previous conversion data out on DATA OUT. Data changes on the falling edge of I/O CLOCK. It transfers control of the conversion to the internal state controller on the falling edge of the last I/O CLOCK. |
| REF + 14 | I | Positive reference voltage. The upper reference voltage value (nominally VCC) is applied to REF+. The maximum input voltage range is determined by the difference between the voltage applied to this terminal and the voltage applied to the REF – terminal. |
| REF – 13 | I | Negative reference voltage. The lower reference voltage value (nominally ground) is applied to REF –. |
| VCC 20 | | Positive supply voltage |

† MSB/LSB = Most significant bit /least significant bit

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

| Condition | | Min | Max |
|---|----------|---------|------------------|
| Supply voltage range, V_{CC} (see Note 1) | | -0.5V | 6.5 V |
| Input voltage range, V_I (any input) | | - 0.3 V | $V_{CC} + 0.3 V$ |
| Output voltage range, V_O | | - 0.3 V | $V_{CC} + 0.3 V$ |
| Positive reference voltage, V_{ref+} | | - | $V_{CC} + 0.1 V$ |
| Negative reference voltage, V_{ref-} | | -0.1V | - |
| Peak input current, I_I (any input) | | -20 mA | +20 mA |
| Peak total input current, I_I (all inputs) | | -30 mA | +30 mA |
| Operating free-air temperature range, T_A : | TLC2543C | 0 °C | 70 °C |
| | TLC2543I | -40 °C | 85 °C |
| Storage temperature range, T_{stg} | | -65 °C | 150 °C |
| Lead Temperature (Soldering, 10 seconds) | | - | 245 °C |

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminal with REF – and GND wired together (unless otherwise noted).

recommended operating conditions

| | | MIN | NOM | MAX | UNIT |
|---|-----------------------------|-------|-----|----------------|------|
| Supply voltage, V_{CC} | | 4.5 | 5 | 5.5 | V |
| Positive reference voltage, V_{ref+} (see Note 2) | | VCC | | | V |
| Negative reference voltage, V_{ref-} (see Note 2) | | 0 | | | V |
| Differential reference voltage, $V_{ref+} - V_{ref-}$ (see Note 2) | | 2.5 | VCC | $V_{CC} + 0.1$ | V |
| Analog input voltage (see Note 2) | | 0 | | | V |
| High-level control input voltage, V_{IH} | $V_{CC} = 4.5 V$ to $5.5 V$ | 2 | | | V |
| Low-level control input voltage, V_{IL} | $V_{CC} = 4.5 V$ to $5.5 V$ | 0.8 | | | V |
| Clock frequency at I/O CLOCK | | 0 | | | MHz |
| Setup time, address bits at DATA INPUT before I/O CLOCK, $t_{su}(A)$ (see Figure 4) | | 100 | | | ns |
| Hold time, address bits after I/O CLOCK, $t_h(A)$ (see Figure 4) | | 0 | | | ns |
| Hold time, CS low after last I/O CLOCK, $t_h(CS)$ (see Figure 5) | | 0 | | | ns |
| Setup time, CS low before clocking in first address bit, $t_{su}(CS)$ (see Note 3 and Figure 5) | | 1.425 | | | µs |
| Pulse duration, I/O CLOCK high, $t_{wH}(I/O)$ | | 120 | | | ns |
| Pulse duration, I/O CLOCK low, $t_{wL}(I/O)$ | | 120 | | | ns |
| Transition time, I/O CLOCK high to low, $t_t(I/O)$ (see Note 4 and Figure 6) | | 1 | | | µs |
| Transition time, DATA INPUT and CS, $t_t(CS)$ | | 10 | | | θs |
| Operating free-air temperature, T_A | TLC2543C | 0 | | | °C |
| | TLC2543I | -40 | | | |
| | | 70 | | | |
| | | 85 | | | |

NO TES: Analog input voltages greater than that applied to REF+ convert as all ones (1111111111), while input voltages less than that applied to REF– convert as all zeros (000000000000).

To minimize errors caused by noise at the \overline{CS} input, the internal circuitry waits for a setup time after \overline{CS} before responding to control input signals. No attempt should be made to clock in an address until the minimum \overline{CS} setup time has elapsed.

This is the time required for the clock input signal to fall from V_{IHmin} to V_{ILmax} or to rise from V_{ILmax} to V_{IHmin} . In the vicinity of normal room temperature, the devices function with input clock transition time as slow as 1 µs for remote data acquisition applications where the sensor and the A/D converter are placed several feet away from the controlling microprocessor.

electrical characteristics over recommended operating free-air temperature range, $V_{CC} = V_{ref+} = 4.5\text{ V to }5.5\text{ V}$, $f(I/O\text{ CLOCK}) = 4.1\text{ MHz}$ (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | TLC2543C, TLC2543I | | | UNIT |
|--|---|---|--------------------|------|---------------|------|
| | | | MIN | TYP† | MAX | |
| V_{OH} | High-level output voltage | $V_{CC} = 4.5\text{ V}$, $I_{OH} = -1.6\text{ mA}$ | 2.4 | | V | |
| | | $V_{CC} = 4.5\text{ V to }5.5\text{ V}$, $I_{OH} = -20\text{ }\mu\text{A}$ | VCC-0.1 | | | |
| V_{OL} | Low-level output voltage | $V_{CC} = 4.5\text{ V}$, $I_{OL} = 1.6\text{ mA}$ | 0.4 | | V | |
| | | $V_{CC} = 4.5\text{ V to }5.5\text{ V}$, $I_{OL} = 20\text{ }\mu\text{A}$ | 0.1 | | | |
| I_{OZ} | High-impedance off-state output current | $V_O = V_{CC}$, \overline{CS} at V_{CC} | 1 | 2.5 | μA | |
| | | $V_O = 0$, \overline{CS} at V_{CC} | 1 | -2.5 | | |
| I_{IH} | High-level input current | $V_I = V_{CC}$ | 1 | 2.5 | μA | |
| I_{IL} | Low-level input current | $V_I = 0$ | 1 | -2.5 | μA | |
| I_{CC} | Operating supply current | \overline{CS} at 0 V | 1 | 2.5 | mA | |
| $I_{CC(PD)}$ | Power-down current | For all digital inputs, $0 \leq V_I \leq 0.5\text{ V}$ or $V_I \geq V_{CC} - 0.5\text{ V}$ | 4 | 25 | μA | |
| Selected channel leakage current | | Selected channel at V_{CC} , Unselected channel at 0 V | 1 | | μA | |
| | | Selected channel at 0 V, Unselected channel at V_{CC} | -1 | | | |
| Maximum static analog reference current into REF + | | $V_{ref+} = V_{CC}$, $V_{ref-} = \text{GND}$ | 1 | 2.5 | μA | |
| C_i | Input capacitance | Analog inputs | 30 | 60 | pF | |
| | | Control inputs | 5 | 15 | | |

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

operating characteristics over recommended operating free-air temperature range, VCC = Vref+ = 4.5 V to 5.5 V, f(I/O CLOCK) = 4.1 MHz

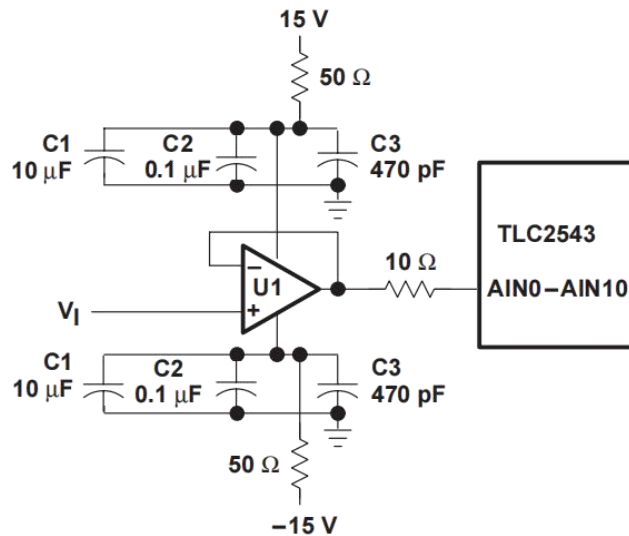
| PARAMETER | | TEST CONDITIONS | MIN | TYP† | MAX | UNIT |
|--|--|-----------------------------|-----|--|-------|-------------------|
| E _L | Linearity error (see Note 5) | See Figure 2 | | | ±1 | LSB |
| E _D | Differential linearity error | See Figure 2 | | | ±1 | LSB |
| E _O | Offset error (see Note 6) | See Note 2 and Figure 2 | | | ±1.5 | LSB |
| E _G | Gain error (see Note 6) | See Note 2 and Figure 2 | | | ±1 | LSB |
| E _T | Total unadjusted error (see Note 7) | | | | ±1.75 | LSB |
| Self-test output code (see Table 3 and Note 8) | | DATA INPUT = 1011 | | 2048 | | |
| | | DATA INPUT = 1100 | | 0 | | |
| | | DATA INPUT = 1101 | | 4095 | | |
| t _{conv} | Conversion time | See Figures 9–14 | | 8 | 10 | μs |
| t _c | Total cycle time (access, sample, and conversion) | See Figures 9–14 and Note 9 | | 10+total I/O CLOCK periods+td(I/O-EOC) | | μs |
| t _{acq} | Channel acquisition time (sample) | See Figures 9–14 and Note 9 | 4 | | 12 | I/O CLOCK periods |
| t _v | Valid time, DATA OUT remains valid after I/O CLOCK↓ | See Figure 6 | 10 | | | ns |
| t _{d(I/O-DATA)} | Delay time, I/O CLOCK↓ to DATA OUT valid | See Figure 6 | | | 150 | ns |
| t _{d(I/O-EOC)} | Delay time, last I/O CLOCK↓ to EOC↓ | See Figure 7 | | 1.5 | 2.2 | μs |
| t _{d(EOC-DATA)} | Delay time, EOC↑ to DATA OUT (MSB / LSB) | See Figure 8 | | | 100 | ns |
| t _{PZH} , t _{PZL} | Enable time, \overline{CS} ↓ to DATA OUT (MSB / LSB driven) | See Figure 3 | | 0.7 | 1.3 | μs |
| t _{PHZ} , t _{PLZ} | Disable time, \overline{CS} ↑ to DATA OUT (high impedance) | See Figure 3 | | 70 | 150 | ns |
| t _{r(EOC)} | Rise time, EOC | See Figure 8 | | 15 | 50 | ns |
| t _{f(EOC)} | Fall time, EOC | See Figure 7 | | 15 | 50 | ns |
| t _{r(bus)} | Rise time, data bus | See Figure 6 | | 15 | 50 | ns |
| t _{f(bus)} | Fall time, data bus | See Figure 6 | | 15 | 50 | ns |
| t _{d(I/O-CS)} | Delay time, last I/O CLOCK↓ to \overline{CS} ↓ to abort conversion (see Note 10) | | | | 5 | μs |

† All typical values are at TA = 25°C.

NOTES: 2. Analog input voltages greater than that applied to REF + convert as all ones (1111111111), while input voltages less than that applied to REF – convert as all zeros (0000000000).

- Linearity error is the maximum deviation from the best straight line through the A/D transfer characteristics.
- Gain error is the difference between the actual midstep value and the nominal midstep value in the transfer diagram at the specified gain point after the offset error has been adjusted to zero. Offset error is the difference between the actual midstep value and the nominal midstep value at the offset point.
- Total unadjusted error comprises linearity, zero-scale, and full-scale errors.
- Both the input address and the output codes are expressed in positive logic.
- I/O CLOCK period = 1 / (I/O CLOCK frequency) (see Figure 7).
- Any transitions of \overline{CS} are recognized as valid only when the level is maintained for a setup time. \overline{CS} must be taken low at $\leq 5\mu\text{s}$ of the tenth I/O CLOCK falling edge to ensure a conversion is aborted. Between $5\mu\text{s}$ and $10\mu\text{s}$, the result is uncertain as to whether the conversion is aborted or the conversion results are valid.

Parameter Measurement Information



| LOCATION | DESCRIPTION | PART NUMBER |
|----------|-------------------------------------|---------------------------------------|
| U1 | OP27 | — |
| C1 | 10-μF 35-V tantalum capacitor | — |
| C2 | 0.1-μF ceramic NPO SMD capacitor | AVX 12105C104KA105 or equivalent |
| C3 | 470-pF porcelain Hi-Q SMD capacitor | Johanson 201S420471JG4L or equivalent |

Figure 1. Analog Input Buffer to Analog Inputs AIN0 – AIN10

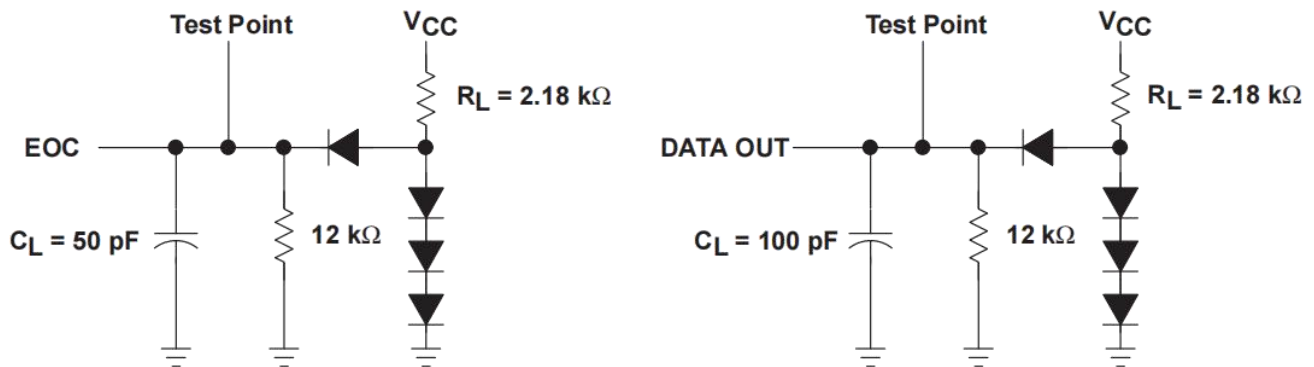


Figure 2. Load Circuits

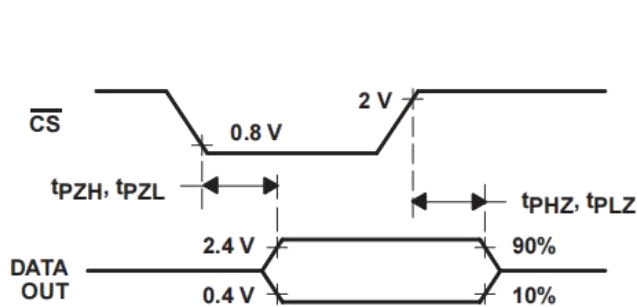


Figure 3. DATA OUT to Hi-Z Voltage Waveforms

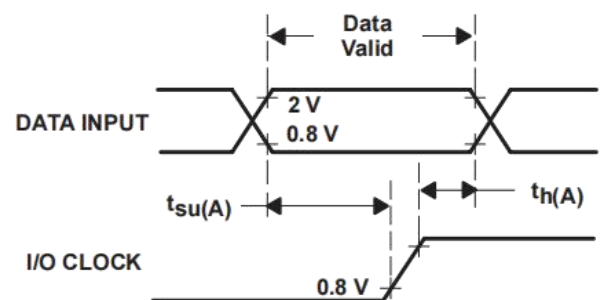
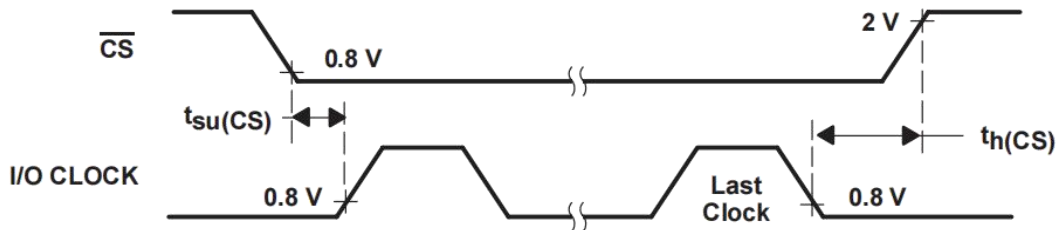


Figure 4. DATA INPUT and I/O CLOCK Voltage Waveforms

Parameter Measurement Information


NOTE A: To ensure full conversion accuracy, it is recommended that no input signal change occurs while a conversion is ongoing.

Figure 5. CS and I/O CLOCK Voltage Waveforms

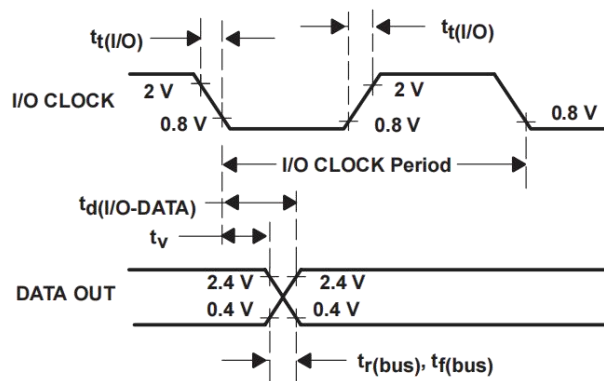


Figure 6. I/O CLOCK and DATA OUT Voltage Waveforms

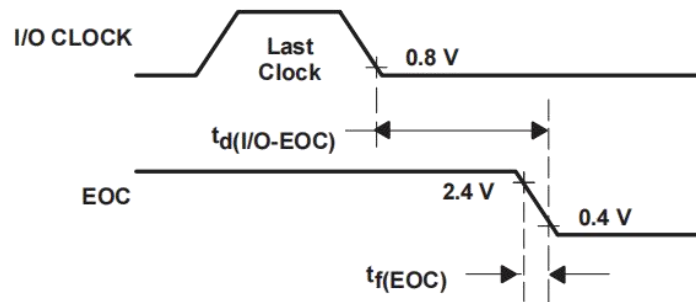


Figure 7. I/O CLOCK and EOC Voltage Waveforms

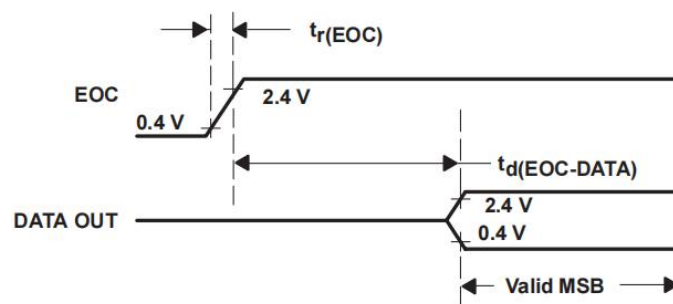
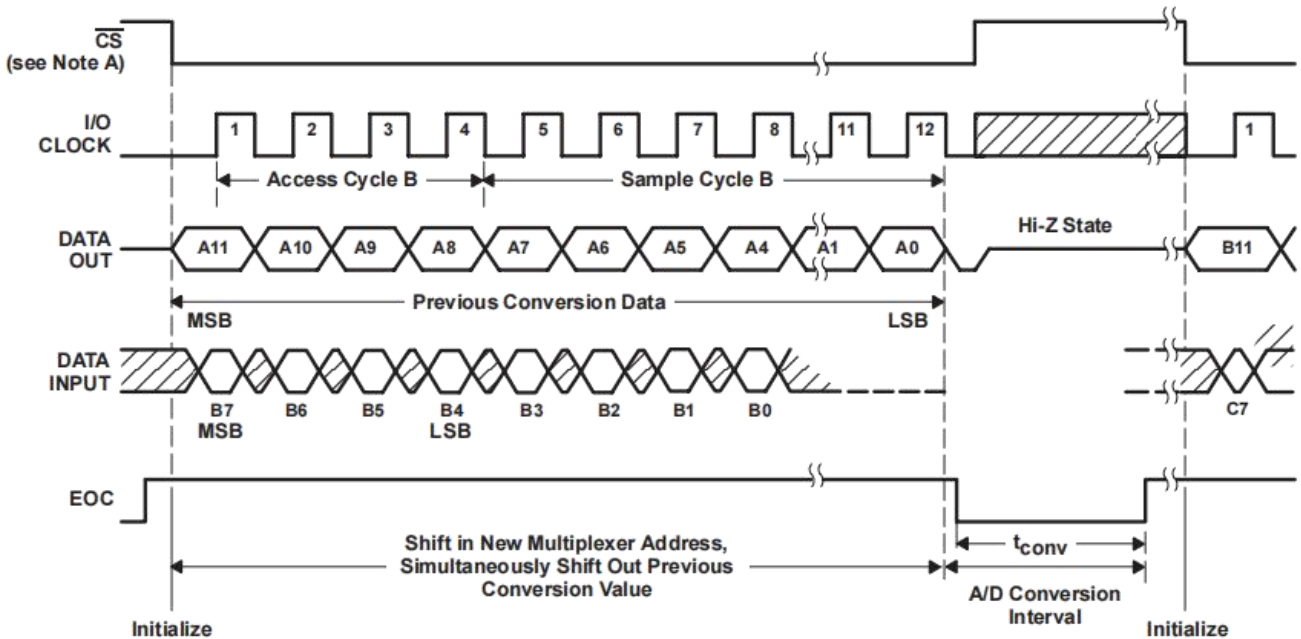
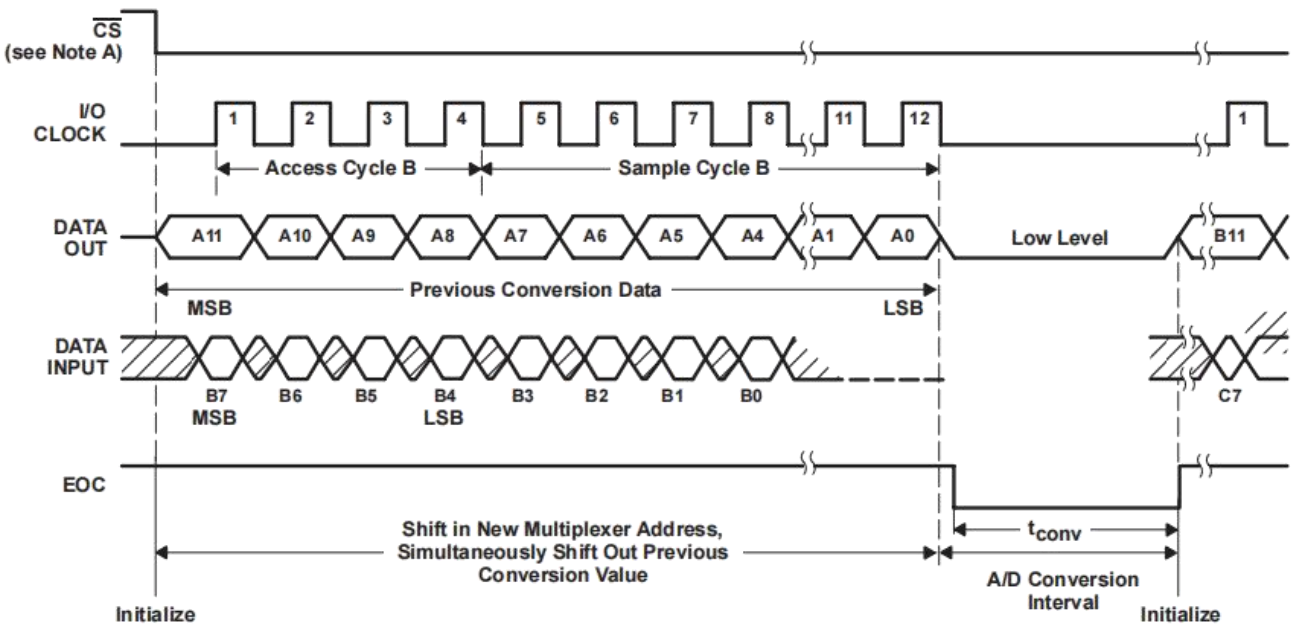


Figure 8. EOC and DATA OUT Voltage Waveforms

Parameter Measurement Information


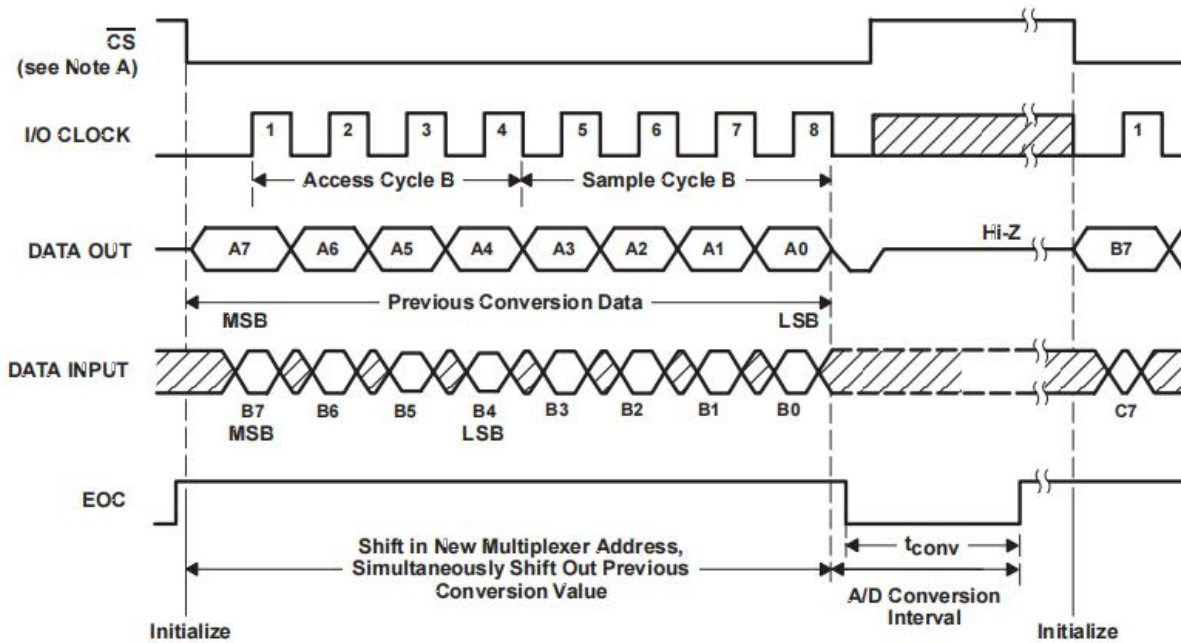
NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after $\overline{CS}\downarrow$ before responding to control input signals. Therefore, no attempt should be made to clock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 9. Timing for 12-Clock Transfer Using CS With MSB First



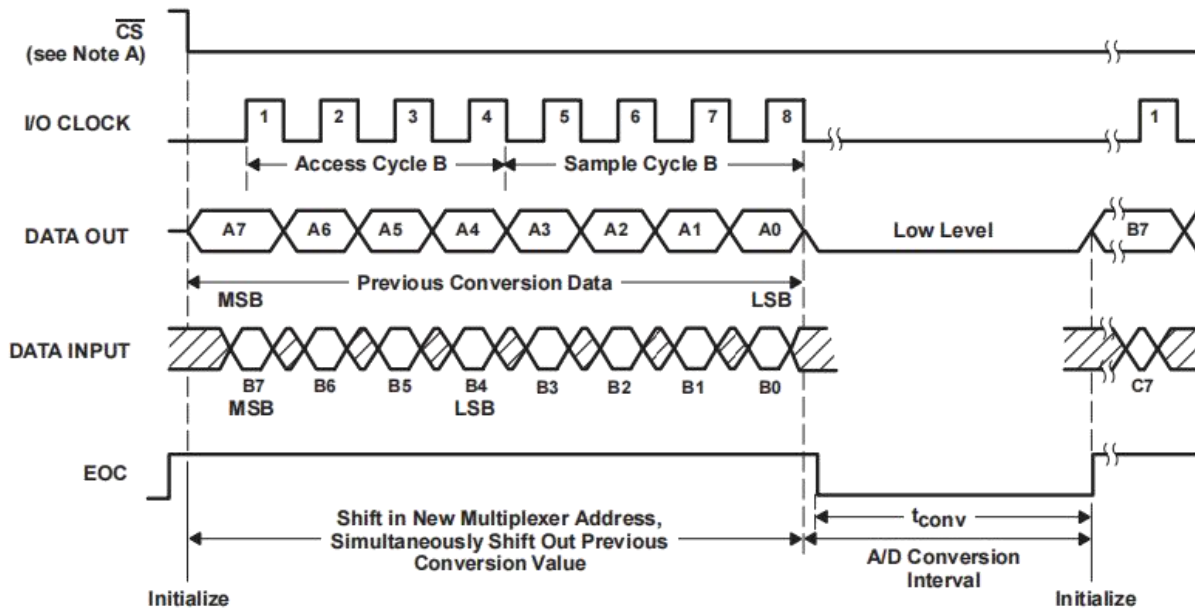
NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after $\overline{CS}\downarrow$ before responding to control input signals. Therefore, no attempt should be made to clock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 10. Timing for 12-Clock Transfer Not Using CS With MSB First

Parameter Measurement Information


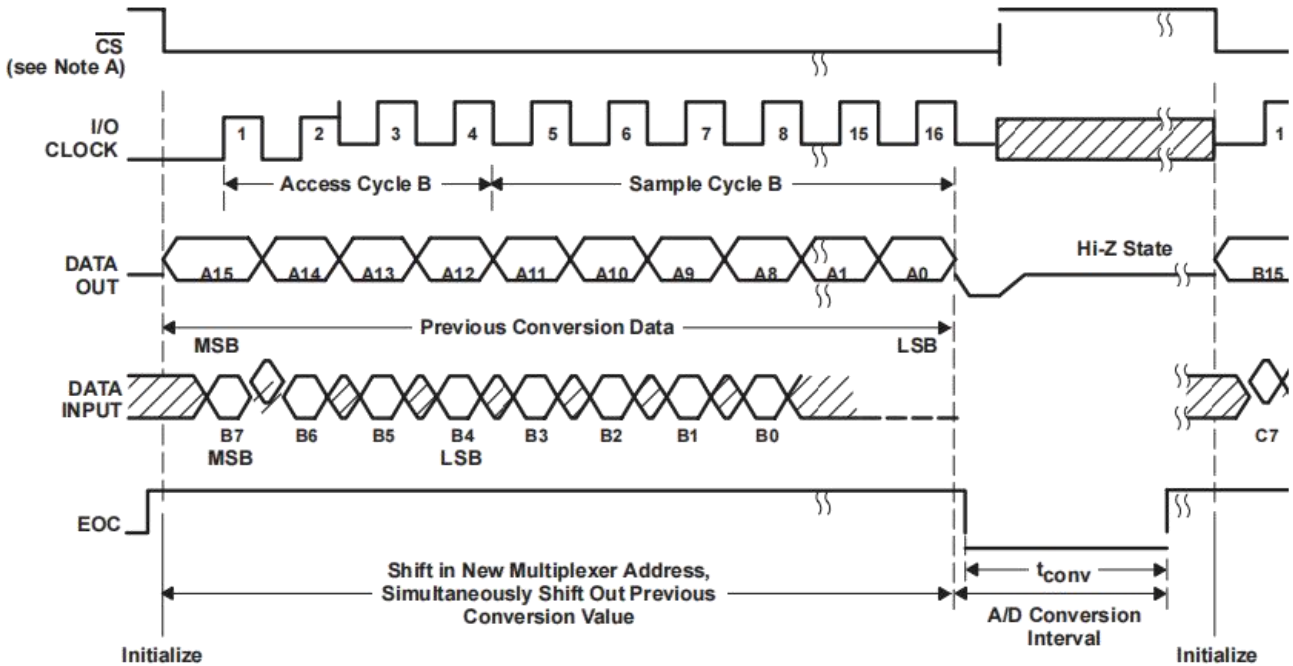
NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after $\overline{CS}\downarrow$ before responding to control input signals. Therefore, no attempt should be made to dock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 11. Timing for 8-Clock Transfer Using CS With MSB First



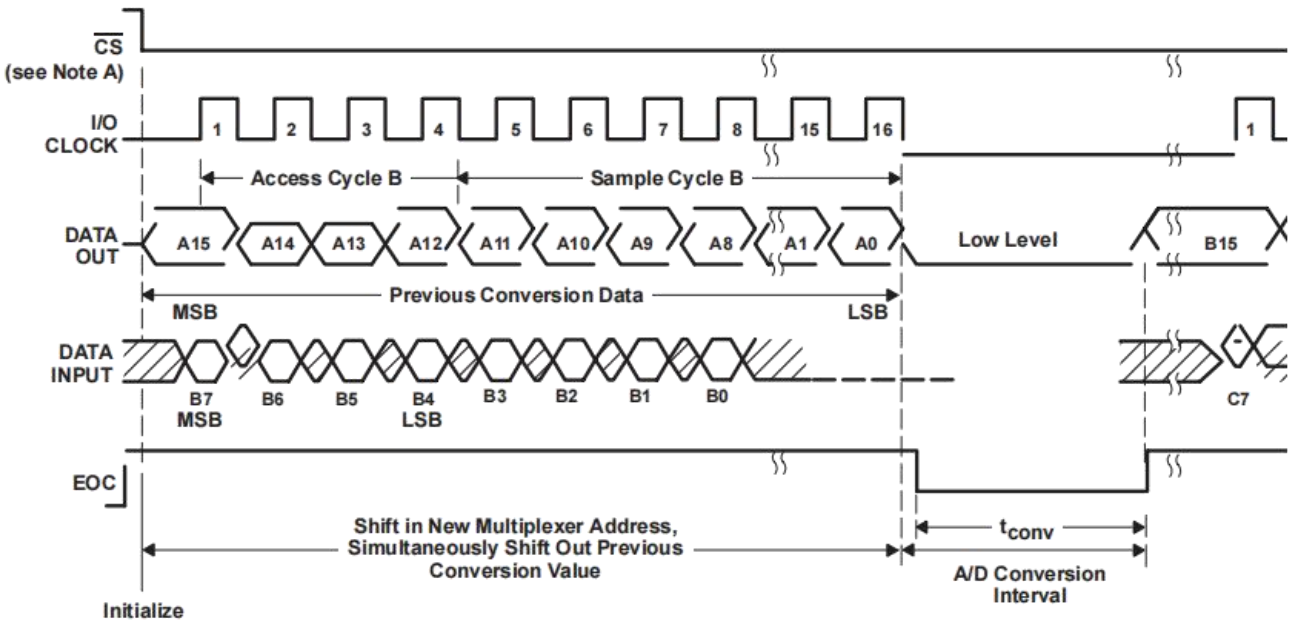
NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after $\overline{CS}\downarrow$ before responding to control input signals. Therefore, no attempt should be made to dock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 12. Timing for 8-Clock Transfer Not Using CS With MSB First

Parameter Measurement Information


NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after \overline{CS} before responding to control input signals. Therefore, no attempt should be made to clock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 13. Timing for 16-Clock Transfer Using CS With MSB First

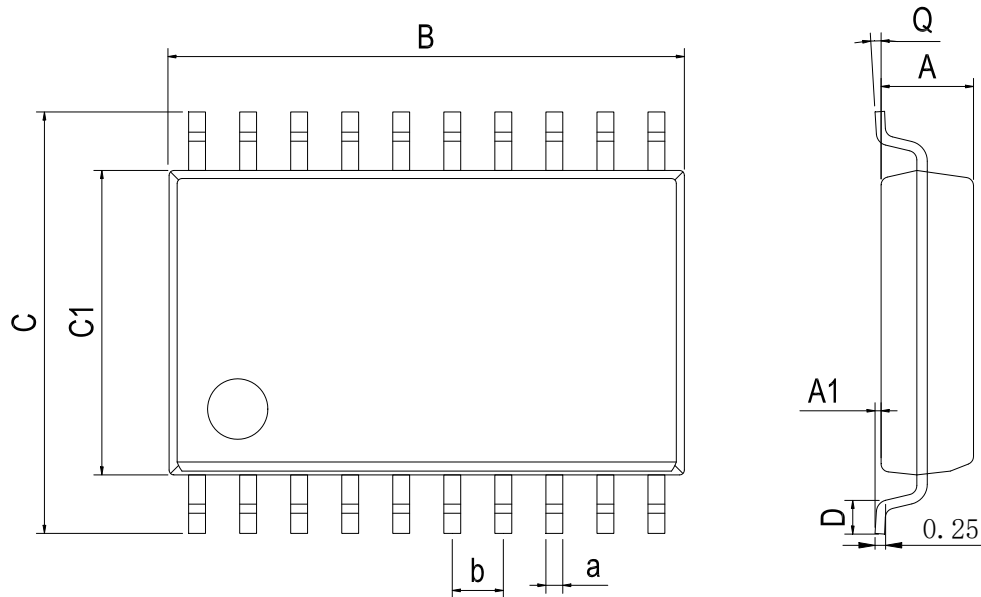


NOTE A: To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for a setup time after \overline{CS} before responding to control input signals. Therefore, no attempt should be made to clock in an address until the minimum \overline{CS} setup time has elapsed.

Figure 14. Timing for 16-Clock Transfer Not Using CS With MSB First

Physical Dimensions

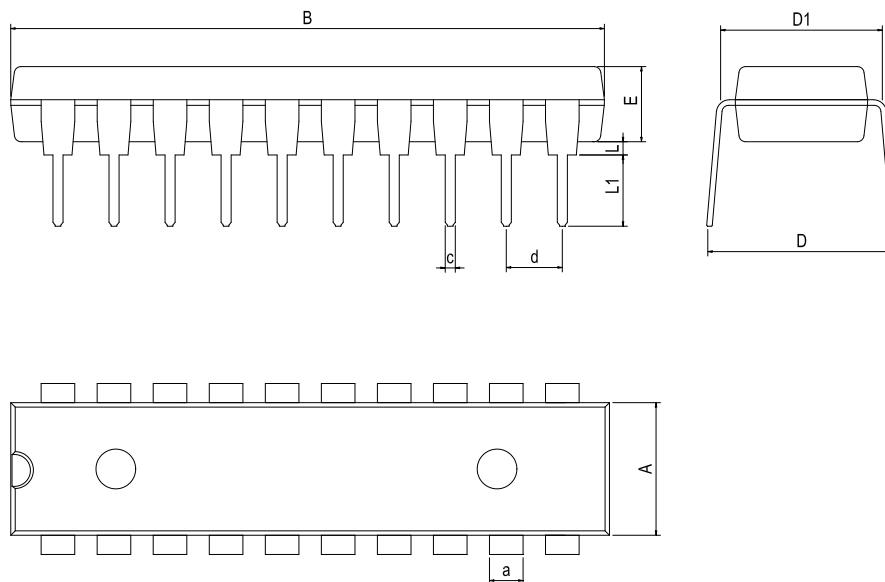
SOP-20W



Dimensions In Millimeters(SOP-20W)

| Symbol: | A | A1 | B | C | C1 | D | Q | a | b |
|---------|------|------|-------|-------|------|------|----|------|----------|
| Min: | 2.10 | 0.05 | 12.50 | 10.21 | 7.40 | 0.45 | 0° | 0.35 | 1.27 BSC |
| Max: | 2.50 | 0.25 | 13.00 | 10.61 | 7.60 | 1.25 | 8° | 0.45 | |

DIP-20



Dimensions In Millimeters(DIP-20)

| Symbol: | A | B | D | D1 | E | L | L1 | a | c | d |
|---------|------|-------|------|------|------|------|------|------|------|----------|
| Min: | 6.10 | 24.95 | 8.10 | 7.42 | 3.10 | 0.50 | 3.00 | 1.50 | 0.40 | 2.54 BSC |
| Max: | 6.68 | 26.55 | 10.9 | 7.82 | 3.55 | 0.70 | 3.60 | 1.55 | 0.50 | |

Revision History

| DATE | REVISION | PAGE |
|-----------|--|-------------|
| 2019-8-6 | New | 1-14 |
| 2023-8-26 | Update encapsulation type、Update Lead Temperature、Updated DIP-20 dimension | 1、 4、 12 |
| 2024-2-22 | Update packages model SOP-20W | 1 |

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